

### IGBT

TRENCHSTOP<sup>™</sup> IGBT4 Low Power Chip IGC36T120T8L

Data Sheet

### Industrial Power Control

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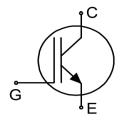
### TRENCHSTOP<sup>™</sup> IGBT4 Low Power Chip

### Features:

- 1200V trench & field stop technology
- Low switching losses
- Positive temperature coefficient
- Easy paralleling

#### **Recommended for:**

- Low / medium power modules
- Applications:
- Low / medium power drives



Chip Type	V <sub>CE</sub>	<b>I</b> Cn <sup>1</sup>	Die Size	Package
IGC36T120T8L	1200V	35A	6.36mm x 5.67mm	Sawn on foil

### **Mechanical Parameters**

Die size		6.36 x 5.67			
Emitter pad size		See chip drawing	mm²		
Gate pad size		0.826 x 1.31			
Area total		36.06			
Thickness		115	μm		
Wafer size		200	mm		
Maximum possible chips per wafer		743			
Passivation frontside		Photoimide	Photoimide		
Pad metal		3200nm AlSiCu			
Backside metal		Ni Ag – system To achieve a reliable solder connection it is strongly recommended not to consume the Ni layer completely during production process			
Die bond Electrically conductive epoxy glue and soft solo			older		
Wire bond		Al, ≤500µm			
Reject ink dot size		Ø 0.65mm; max. 1.2mm			
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, temperature 17°C – 2 <6 months	25°C,		
	for open MBB bags	Acc. to IEC62258-3: atmosphere >99% Nitrogen of humidity <25%RH, temperature 17°C – 25°C, <6			

<sup>&</sup>lt;sup>1</sup> Nominal collector current at  $T_{C}=100^{\circ}C$  for chip packaged in power modules, see application example cited on page 5.



### **Maximum Ratings**

Parameter	Symbol	Value	Unit
Collector-emitter voltage, T <sub>vj</sub> =25°C	V <sub>CE</sub>	1200	V
DC collector current, limited by $T_{vj max}^2$	I <sub>C</sub>	-	А
Pulsed collector current, $t_p$ limited by $T_{vj max}^3$	I <sub>C,puls</sub>	105	А
Gate-emitter voltage	V <sub>GE</sub>	±20	V
Operating junction temperature	T <sub>vj</sub>	-40 +175	°C
Short circuit data $^{3/4}$ V <sub>GE</sub> =15V, V <sub>CC</sub> =800V, T <sub>vj</sub> =150°C	t <sub>sc</sub>	10	μs

### Static Characteristics (tested on wafer), Tvj=25°C

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Collector-emitter breakdown voltage	V <sub>(BR)CES</sub>	V <sub>GE</sub> =0V, <i>I</i> <sub>C</sub> =1.2mA	1200	-	-	
Collector-emitter saturation voltage	V <sub>CEsat</sub>	V <sub>GE</sub> =15V, <i>I</i> <sub>C</sub> =35A	1.58	1.85	2.07	V
Gate-emitter threshold voltage	V <sub>GE(th)</sub>	$I_{\rm C}$ =1.2mA, $V_{\rm GE}$ = $V_{\rm CE}$	5.3	5.8	6.3	
Zero gate voltage collector current	I <sub>CES</sub>	V <sub>CE</sub> =1200V, V <sub>GE</sub> =0V	-	-	5	μA
Gate-emitter leakage current	I <sub>GES</sub>	$V_{CE}$ =0V, $V_{GE}$ =20V	-	-	120	nA
Integrated gate resistor	r <sub>G</sub>			none		Ω

### **Electrical Characteristics** <sup>3</sup>

Parameter	Symbol	Conditions	Value			Unit
	Symbol		min.	typ.	max.	Unit
Collector-emitter saturation voltage	V <sub>CEsat</sub>	V <sub>GE</sub> =15V, <i>I</i> <sub>C</sub> =35A, <i>T</i> <sub>vj</sub> =150°C	-	2.25	-	V
Input capacitance	C <sub>ies</sub>	$V_{CE}=25V,$	-	2000	-	~F
Reverse transfer capacitance	C <sub>res</sub>	V <sub>GE</sub> =0V, <i>f</i> =1MHz <i>T</i> <sub>vj</sub> =25°C	-	70	-	pF

 <sup>&</sup>lt;sup>2</sup> Depending on thermal properties of assembly.
<sup>3</sup> Not subject to production test - verified by design/characterization.

<sup>&</sup>lt;sup>4</sup> Allowed number of short circuits: <1000; time between short circuits: >1s.



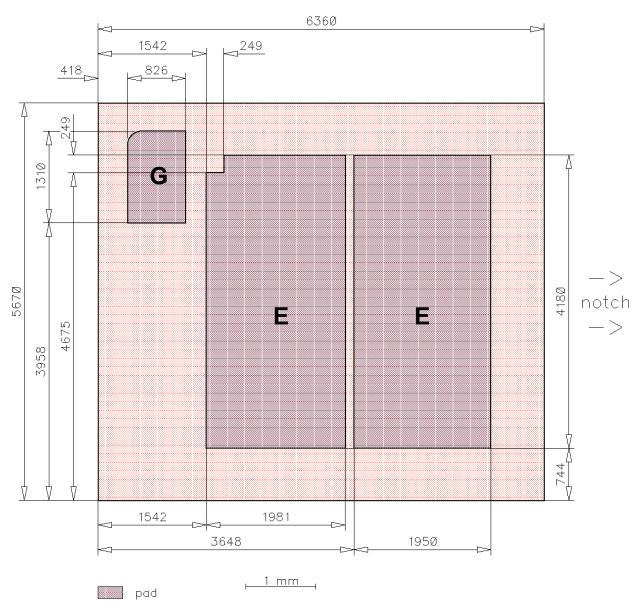
### **Further Electrical Characteristics**

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

Application example	FP35R12W2T4_B11	Rev. 2.0
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### **Chip Drawing**



Die-Size 6360 um x 5670 um

 $\mathbf{E} = \text{Emitter}$ 

G = Gate



### **Bare Die Product Specifics**

Test coverage at wafer level cannot cover all application conditions. Therefore it is recommended to test all characteristics which are relevant for the application at package level, including RBSOA and SCSOA.

#### Description

AQL 0.65 for visual inspection according to failure catalogue
Electrostatic Discharge Sensitive Device according to MIL-STD 883

#### **Revision History**

Revision	Subjects (major changes since last revision)	Date
2.0	Final data sheet	18.02.2015
2.1	Update disclaimer	20.08.2015

### **Relevant Application Notes**



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